

Introduction

Thin films are the fundamental building blocks for many technologies, including electronic, electrochemical, and optical devices. However, they are unstable against capillary forces. Capillarity (surface tension) drives a process in thin films known as solid-state dewetting: the edges retract, holes can form, and the film breaks up into islands of material with characteristic microstructural features. This process occurs below the

Dewetting phenomena



Governing equations

The chemical potential μ is proportional to the mean curvature κ of the film surface:

 $\mu(s_1, s_2) = \gamma \Omega \kappa(s_1, s_2)$

where s_1 and s_2 are the arc length coordinates, γ is the surface energy, and Ω is the volume per atom. Using the Nernst-Einstein relation and Fick's law, the non-dimensional velocity of a surface along its normal is

$$v_n = -\Delta_s \kappa(s_1, s_2)$$

where Δ_s is the Laplace-Beltrami operator (i.e., the surface Laplacian). This can be generalized for anisotropic materials.

Mullins, J. Appl. Phys., 28, 1957

The non-dimensionalized phase field formulation for dewetting is

$$\frac{\partial \phi}{\partial t} = \nabla \cdot$$
$$\mu = \phi^3$$

where ϕ is the phase field variable, t is time, μ is the chemical potential, and ε is related to the interface width. This is subject to the boundary condition

$$\epsilon \frac{\partial \phi}{\partial \mathbf{n}} + \frac{\sqrt{2}}{2}(\phi^2 - 1)\cos\theta = 0$$

Capillary Instabilities on Thin Solid Films

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film's melting point via capillary-driven surface selfdiffusion. Understanding dewetting is critical for the prevention of thermal degradation in micro- and nanoscale systems. For anisotropic materials, it also offers a new avenue for the manufacture of stable, complex, small-scale geometries. We present a variety of theoretical and computational studies to understand and control dewetting microstructures.

$$((1-\phi^2)\nabla\mu)$$

 $-\phi-\epsilon^2\Delta\phi$

where **n** is normal to the boundary and θ is the contact angle of the film on the substrate. The periodic boundary condition

$$\frac{\partial \phi}{\partial \mathbf{n}} = 0$$

applies on all other boundaries, and the mass conservation condition

$$\frac{\partial \mu}{\partial \mathbf{n}} = 0$$

applies on all boundaries. This formulation can also be generalized to anisotropic materials.

Questions: How does strong anisotropy affect edge retraction? Which parameters dominate dewetting behavior?

Results: Consistent with experiments, no valleys are present, predicts a small mass flux towards the rim

Fingering instability analysis

Questions: What drives the fingering instability? What determines the wavelength?

Method: Perturbation analysis for isotropic material, simplified geometry with a circular rim cross-section

dominates.

Zucker *et al.*, in preparation

Method: Perturbation analysis, anisotropy, simplified geometry

Results: Increasing arc length is the main driver, there is a minimum rim size for instability Zucker *et al.*, in preparation

Phase field simulation

Questions: Can we simulate dewetting?

Method: AMDiS: finite element, adaptive-mesh, C++ library for PDEs: www.amdis-fem.org

Results: In progress. Verifying the analytical models, simulating the effects of anisotropy



2D highly anisotropic model

Method: Explicit interface tracking, material is faceted, analytical in space, explicit forward differencing in time

Zucker et al., C. R. Phys. 14, 2013 Kim et al., J. Appl. Phys. 113, 2013



Top: Retraction of an example film, similar to Ni at 900°C. Left: Typical chemical potential and mass flux on the rim. Center: The dependence of edge retraction distance on

experiments.

 $\frac{\Lambda_{\text{critical}}}{2\pi}$

Results: Three drivers of instability contribute: Rayleigh flow, the arc length effect, and divergent retraction. The latter

Corner instability analysis

Questions: What causes the corner instability?





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the contact angle.

Right: the model is in good quantitative agreement with



Left: the three drivers of the fingering instability.

Center: perturbation growth rates for the three separate drivers, and for the net effect vertically (rim height) and horizontally (triple line position), for two different contact angles.

Right: The critical and fastest-growing perturbation wavelength as a function of perturbation amplitude ε .

Left: schematic geometry, informed by experimental observations.

Right: the model predicts that the corner is driven towards a constant rim height and therefore retracts faster than the edges of the hole. This is in excellent agreement with experiments.



Left: simulated films have all relevant features: rims, valleys, hole formation, pinch-off, and edge instabilities. Future work includes predicting dewetting microstructures.

Right: an anisotropic island of material produced as a result of dewetting in a phase field simulation.